

Search Notes

Application/Control No.

10/507,466

Examiner

Shin-Lin Chen

Applicant(s)/Patent under
Reexamination

OSTERMEIER, MARK

Art Unit

1632

SEARCHED

Class	Subclass	Date	Examiner
536	23.1		
536	23.4		
536	24.1		
530	300		
530	350		
424	192.1	12/21/2006	<i>LM</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST, STN, Medline, Caplus, Biosis, Scisearch, Lifesci, parentw reviewed and updated.	12/21/2006	<i>SM</i>